

FDMA530PZ

Single P-Channel PowerTrench® MOSFET

-30V, -6.8A, 35mΩ

Features

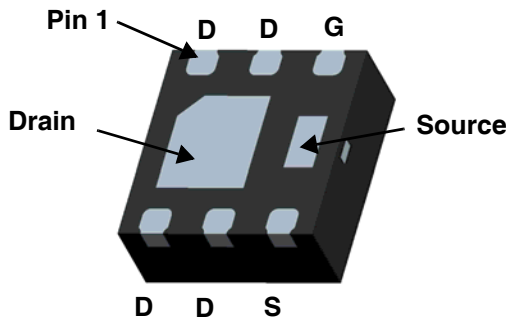
- Max $r_{DS(on)}$ = 35mΩ at $V_{GS} = -10V$, $I_D = -6.8A$
- Max $r_{DS(on)}$ = 65mΩ at $V_{GS} = -4.5V$, $I_D = -5.0A$
- Low profile - 0.8mm maximum - in the new package MicroFET 2X2 mm
- HBM ESD protection level > 3kV typical (Note 3)
- Free from halogenated compounds and antimony oxides
- RoHS Compliant



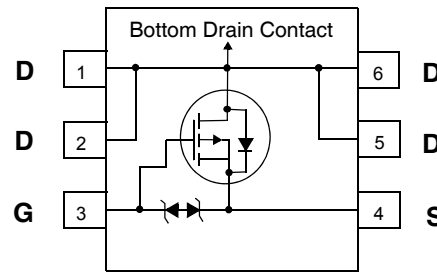
General Description

This device is designed specifically for battery charge or load switching in cellular handset and other ultraportable applications. It features a MOSFET with low on-state resistance.

The MicroFET 2X2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.



MicroFET 2X2 (Bottom View)



MOSFET Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Ratings | Units |
|----------------|--|-------------|------------------|
| V_{DS} | Drain to Source Voltage | -30 | V |
| V_{GS} | Gate to Source Voltage | ± 25 | V |
| I_D | Drain Current -Continuous (Note 1a) | -6.8 | A |
| | -Pulsed | -24 | |
| P_D | Power Dissipation (Note 1a) | 2.4 | W |
| | Power Dissipation (Note 1b) | 0.9 | |
| T_J, T_{STG} | Operating and Storage Junction Temperature Range | -55 to +150 | $^\circ\text{C}$ |

Thermal Characteristics

| | | | |
|-----------------|---|-----|--------------------|
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Note 1a) | 52 | $^\circ\text{C/W}$ |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Note 1b) | 145 | |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|-----------|--------------|-----------|------------|------------|
| 530 | FDMA530PZ | MicroFET 2X2 | 7" | 8mm | 3000 units |

Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|--------|-----------|-----------------|-----|-----|-----|-------|

Off Characteristics

| | | | | | | |
|--------------------------------------|---|--|-----|-----|----------|----------------------|
| BV_{DSS} | Drain to Source Breakdown Voltage | $I_D = -250\mu\text{A}, V_{GS} = 0\text{V}$ | -30 | | | V |
| $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | Breakdown Voltage Temperature Coefficient | $I_D = -250\mu\text{A}$, referenced to 25°C | | -23 | | mV/ $^\circ\text{C}$ |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = -24\text{V}, V_{GS} = 0\text{V}$ | | | -1 | μA |
| I_{GSS} | Gate to Source Leakage Current | $V_{GS} = \pm 25\text{V}, V_{DS} = 0\text{V}$ | | | ± 10 | μA |

On Characteristics

| | | | | | | |
|--|--|---|----|------|----|----------------------|
| $V_{GS(th)}$ | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}, I_D = -250\mu\text{A}$ | -1 | -2.1 | -3 | V |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | $I_D = -250\mu\text{A}$, referenced to 25°C | | 5.4 | | mV/ $^\circ\text{C}$ |
| $r_{DS(on)}$ | Static Drain to Source On Resistance | $V_{GS} = -10\text{V}, I_D = -6.8\text{A}$ | | 30 | 35 | m Ω |
| | | $V_{GS} = -4.5\text{V}, I_D = -5.0\text{A}$ | | 52 | 65 | |
| | | $V_{GS} = -10\text{V}, I_D = -6.8\text{A}, T_J = 125^\circ\text{C}$ | | 43 | 63 | |
| g_{FS} | Forward Transconductance | $V_{DS} = -10\text{V}, I_D = -6.8\text{A}$ | | 17 | | S |

Dynamic Characteristics

| | | | | | | |
|-----------|------------------------------|---|---|-----|------|----------|
| C_{iss} | Input Capacitance | $V_{DS} = -15\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$ | | 805 | 1070 | pF |
| C_{oss} | Output Capacitance | | | 155 | 210 | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 130 | 195 | pF |
| R_g | Gate Resistance | | 1 | 18 | 38 | Ω |

Switching Characteristics

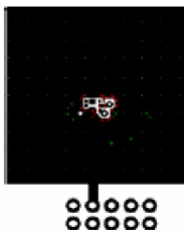
| | | | | | | | |
|--------------|-------------------------------|---|--|----|-----|----|----|
| $t_{d(on)}$ | Turn-On Delay Time | $V_{DD} = -15\text{V}, I_D = -6.8\text{A}$ $V_{GS} = -10\text{V}, R_{GEN} = 6\Omega$ | | 6 | 12 | ns | |
| t_r | Rise Time | | | 21 | 34 | ns | |
| $t_{d(off)}$ | Turn-Off Delay Time | | | 43 | 69 | ns | |
| t_f | Fall Time | | | 31 | 50 | ns | |
| Q_g | Total Gate Charge | | $V_{GS} = -10\text{V}$ | | 16 | 24 | nC |
| Q_g | Total Gate Charge | $V_{GS} = -5\text{V}$ | $V_{DD} = -15\text{V}$ $I_D = -6.8\text{A}$ | | 9 | 11 | nC |
| Q_{gs} | Gate to Source Gate Charge | | | | 3.1 | | nC |
| Q_{gd} | Gate to Drain "Miller" Charge | | | | 4.5 | | nC |

Drain-Source Diode Characteristics

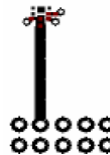
| | | | | | | |
|----------|---|---|--|------|------|----|
| I_S | Maximum Continuous Drain-Source Diode Forward Current | | | -2 | A | |
| V_{SD} | Source to Drain Diode Forward Voltage | $V_{GS} = 0\text{V}, I_S = -2\text{A}$ | | -0.8 | -1.2 | V |
| t_{rr} | Reverse Recovery Time | $I_F = -6.8\text{A}, di/dt = 100\text{A}/\mu\text{s}$ | | 24 | 36 | ns |
| Q_{rr} | Reverse Recovery Charge | | | 19 | 29 | nC |

Notes:

1: $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.



a. $52^\circ\text{C}/\text{W}$ when mounted on a 1 in^2 pad of 2 oz copper



b. $145^\circ\text{C}/\text{W}$ when mounted on a minimum pad of 2 oz copper

2: Pulse Test: Pulse Width < $300\mu\text{s}$, Duty cycle < 2.0%.

3: The diode connected between the gate and the source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

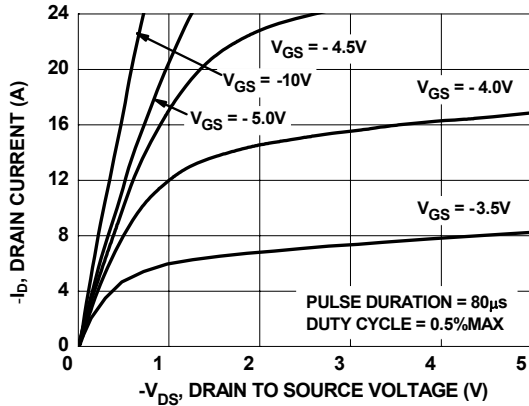


Figure 1. On-Region Characteristics

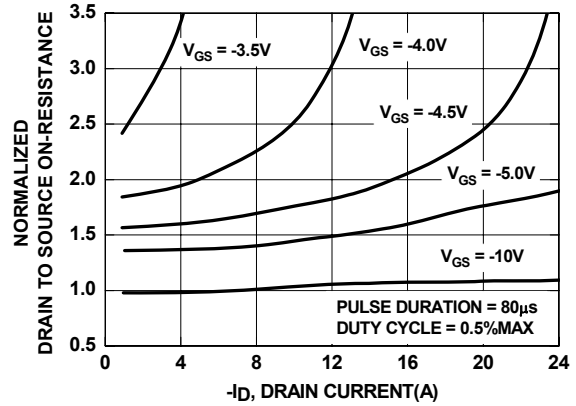


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

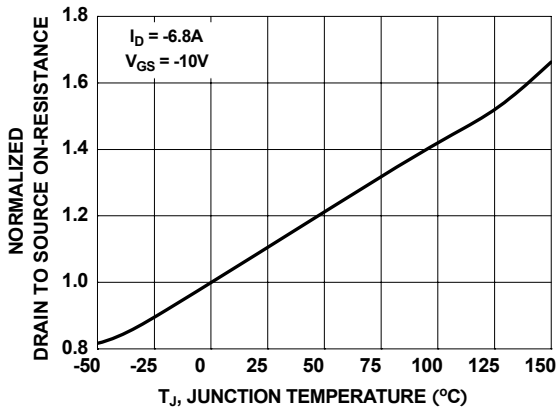


Figure 3. Normalized On-Resistance vs Junction Temperature

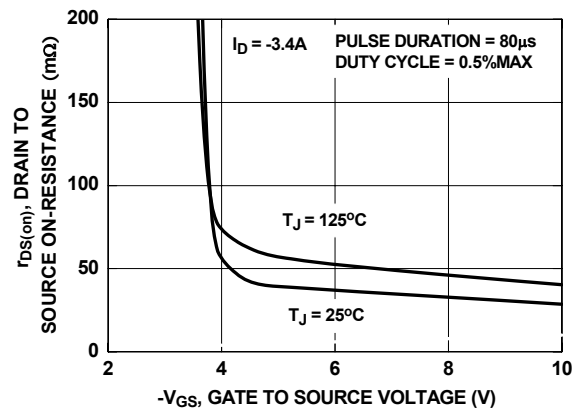


Figure 4. On-Resistance vs Gate to Source Voltage

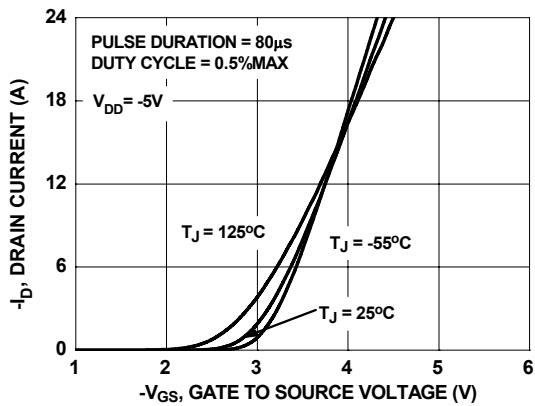


Figure 5. Transfer Characteristics

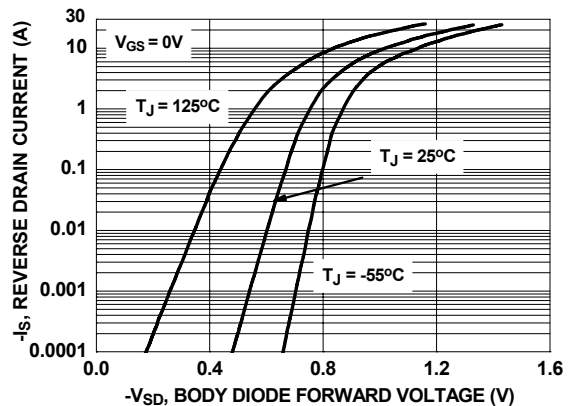


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

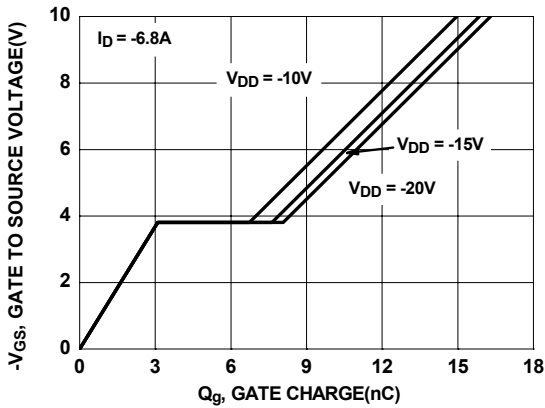


Figure 7. Gate Charge Characteristics

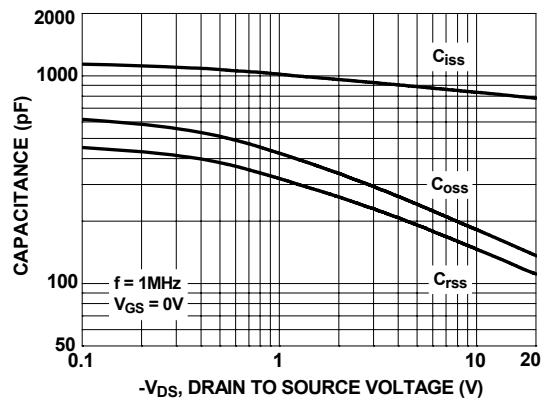


Figure 8. Capacitance vs Drain to Source Voltage

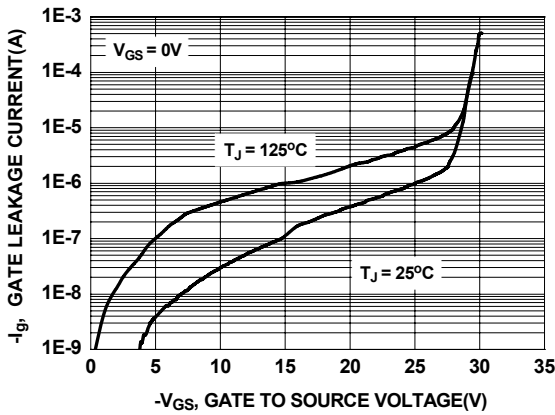


Figure 9. Gate Leakage Current vs Gate to Source Voltage

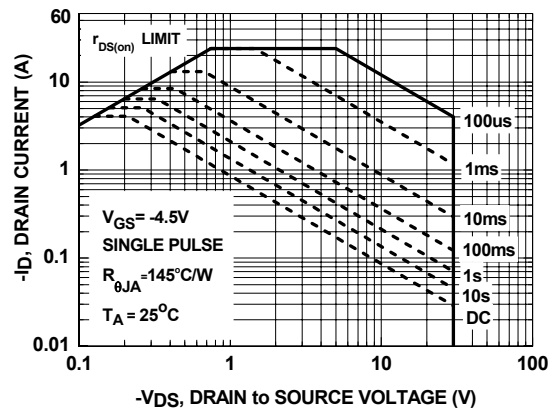


Figure 10. Forward Bias Safe Operating Area

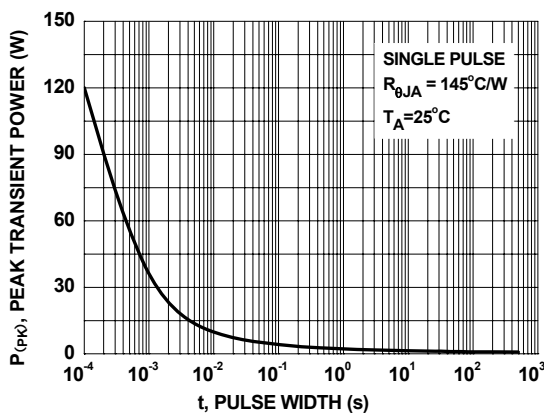


Figure 11. Single Pulse Maximum Power Dissipation

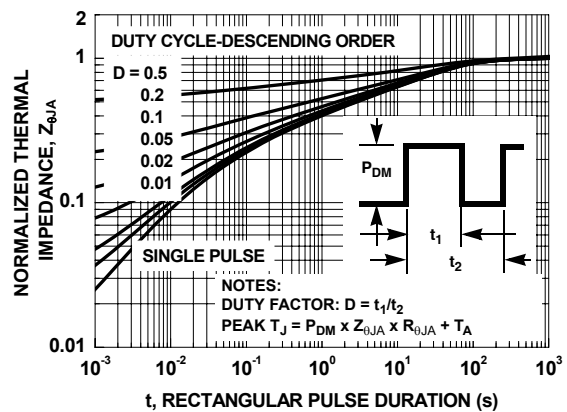
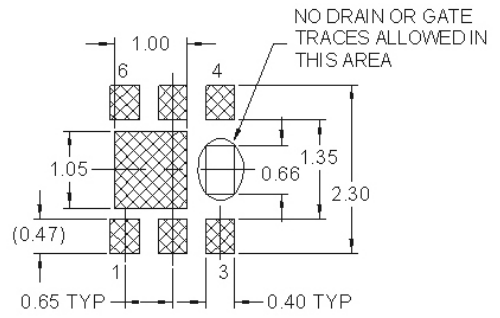
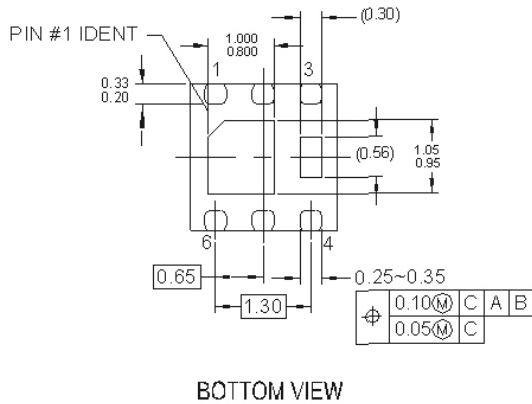
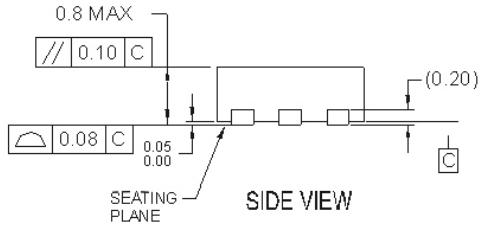
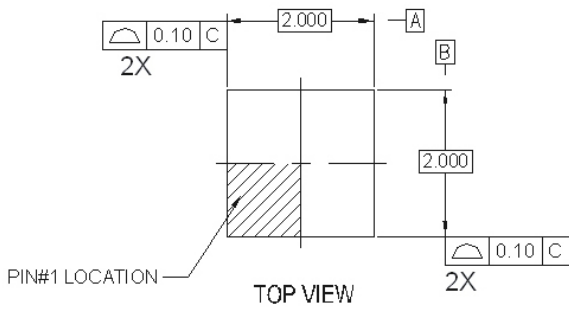
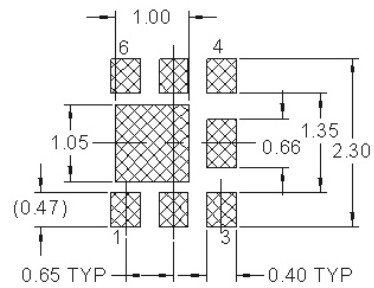


Figure 12. Transient Thermal Response Curve

Dimensional Outline and Pad Layout



RECOMMENDED LAND PATTERN OPT 1



RECOMMENDED LAND PATTERN OPT 2






NOTES:

- A. DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-229 DATED AUG/2003
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. DRAWING FILENAME: MKT-MLP06Lrev2.



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